Cedric J Powell

List of Publications by Year
in descending order

159 papers	14,529 citations	36203 51 h-index	19136 118 g-index
169 all docs	169 docs citations	169 times ranked	9810 citing authors

#	Article	IF	Citations
1	Calculations of electron inelastic mean free paths. V. Data for 14 organic compounds over the 50-2000 eV range. Surface and Interface Analysis, 1994, 21, 165-176.	0.8	2,216
2	Calculations of electorn inelastic mean free paths. II. Data for 27 elements over the 50-2000 eV range. Surface and Interface Analysis, 1991, 17, 911-926.	0.8	1,161
3	Calculations of electron inelastic mean free paths for 31 materials. Surface and Interface Analysis, 1988, 11, 577-589.	0.8	903
4	Calculations of electron inelastic mean free paths. IX. Data for 41 elemental solids over the 50 eV to 30 keV range. Surface and Interface Analysis, 2011, 43, 689-713.	0.8	746
5	Calculations of electron inelastic mean free paths. III. Data for 15 inorganic compounds over the 50-2000 eV range. Surface and Interface Analysis, 1991, 17, 927-939.	0.8	624
6	elsepaâ€"Dirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules. Computer Physics Communications, 2005, 165, 157-190.	3.0	507
7	Evaluation of Calculated and Measured Electron Inelastic Mean Free Paths Near Solid Surfaces. Journal of Physical and Chemical Reference Data, 1999, 28, 19-62.	1.9	465
8	Calculation of electron inelastic mean free paths (IMFPs) VII. Reliability of the TPP-2M IMFP predictive equation. Surface and Interface Analysis, 2003, 35, 268-275.	0.8	403
9	Calculations of electron inelastic mean free paths (IMFPS). IV. Evaluation of calculated IMFPs and of the predictive IMFP formula TPP-2 for electron energies between 50 and 2000 eV. Surface and Interface Analysis, 1993, 20, 77-89.	0.8	397
10	Origin of the Characteristic Electron Energy Losses in Aluminum. Physical Review, 1959, 115, 869-875.	2.7	357
11	Cross sections for ionization of inner-shell electrons by electrons. Reviews of Modern Physics, 1976, 48, 33-47.	16.4	354
12	Calculations of electron inelastic mean free paths. X. Data for 41 elemental solids over the 50â€‰eV to 200â€‰keV range with the relativistic full Penn algorithm. Surface and Interface Analysis, 2015, 47, 871-888.	0.8	270
13	Simulation of electron spectra for surface analysis (SESSA): a novel software tool for quantitative Auger-electron spectroscopy and X-ray photoelectron spectroscopy. Surface and Interface Analysis, 2005, 37, 1059-1067.	0.8	233
14	Precision, accuracy, and uncertainty in quantitative surface analyses by Augerâ€electron spectroscopy and xâ€ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1990, 8, 735-763.	0.9	232
15	Effect of Oxidation on the Characteristic Loss Spectra of Aluminum and Magnesium. Physical Review, 1960, 118, 640-643.	2.7	210
16	Calculations of electron inelastic mean free paths. Surface and Interface Analysis, 2005, 37, 1-14.	0.8	210
17	Comparison of Electron Elastic-Scattering Cross Sections Calculated from Two Commonly Used Atomic Potentials. Journal of Physical and Chemical Reference Data, 2004, 33, 409-451.	1.9	204
18	Oxygen as a surfactant in the growth of giant magnetoresistance spin valves. Journal of Applied Physics, 1997, 82, 6142-6151.	1.1	193

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19	Contrasting Valence-Band Auger-Electron Spectra for Silver and Aluminum. Physical Review Letters, 1973, 30, 1179-1182.	2.9	157
20	Characteristic Energy Losses of 8-keV Electrons in Liquid Al, Bi, In, Ga, Hg, and Au. Physical Review, 1968, 175, 972-982.	2.7	141
21	Practical guides for x-ray photoelectron spectroscopy: First steps in planning, conducting, and reporting XPS measurements. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2019, 37, .	0.9	137
22	Relationships between electron inelastic mean free paths, effective attenuation lengths, and mean escape depths. Journal of Electron Spectroscopy and Related Phenomena, 1999, 100, 137-160.	0.8	136
23	Cross Sections for Inner-Shell Ionization by Electron Impact. Journal of Physical and Chemical Reference Data, 2014, 43, .	1.9	133
24	Experimental determination of electron inelastic mean free paths in 13 elemental solids in the 50 to 5000 eV energy range by elastic-peak electron spectroscopy. Surface and Interface Analysis, 2005, 37, 833-845.	0.8	132
25	Magnetoresistance values exceeding 21% in symmetric spin valves. Journal of Applied Physics, 1995, 78, 273-277.	1.1	127
26	Origin of the Characteristic Electron Energy Losses in Magnesium. Physical Review, 1959, 116, 81-83.	2.7	109
27	Formalism and parameters for quantitative surface analysis by Auger electron spectroscopy and x-ray photoelectron spectroscopy. Surface and Interface Analysis, 1993, 20, 771-786.	0.8	102
28	Electron effective attenuation lengths for applications in Auger electron spectroscopy and x-ray photoelectron spectroscopy. Surface and Interface Analysis, 2002, 33, 211-229.	0.8	101
29	Cross sections for ionization of K, L and M shells of atoms by impact of electrons and positrons with energies up to 1GeV: Analytical formulas. Atomic Data and Nuclear Data Tables, 2009, 95, 871-909.	0.9	98
30	Practical expressions for the mean escape depth, the information depth, and the effective attenuation length in Auger-electron spectroscopy and x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2009, 27, 253-261.	0.9	96
31	Calculations of electron inelastic mean free paths. XII. Data for 42 inorganic compounds over the 50 eV to 200 keV range with the full Penn algorithm. Surface and Interface Analysis, 2019, 51, 427-457.	0.8	92
32	Calculations of Electron Inelastic Mean Free Paths (IMFPs)VI. Analysis of the Gries Inelastic Scattering Model and Predictive IMFP Equation. Surface and Interface Analysis, 1997, 25, 25-35.	0.8	90
33	Calculations of electron inelastic mean free paths. XI. Data for liquid water for energies from 50â€‰eV to 30â€‰keV. Surface and Interface Analysis, 2017, 49, 238-252.	0.8	82
34	Energy and material dependence of the inelastic mean free path of lowâ€energy electrons in solids. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1985, 3, 1338-1342.	0.9	79
35	Practical guide for inelastic mean free paths, effective attenuation lengths, mean escape depths, and information depths in x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2020, 38, .	0.9	77
36	Optimizing the giant magnetoresistance of symmetric and bottom spin valves (invited). Journal of Applied Physics, 1996, 79, 5277.	1.1	75

#	ARTICLE	IF	CITATIONS
37	Information depth and the mean escape depth in Auger electron spectroscopy and x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2003, 21, 274-283.	0.9	74
38	Summary Abstract: Accurate determination of the energies of Auger electrons and photoelectrons from nickel, copper, and gold. Journal of Vacuum Science and Technology, 1982, 20, 625-625.	1.9	73
39	Growth of giant magnetoresistance spin valves using indium as a surfactant. Journal of Applied Physics, 1996, 79, 2491-2496.	1.1	72
40	Artifacts in ballistic magnetoresistance measurements (invited). Journal of Applied Physics, 2004, 95, 7554-7559.	1.1	69
41	Inelastic Scattering Cross Sections for 20-keV Electrons in Al, Be, and Polystyrene. Physical Review, 1966, 145, 195-208.	2.7	66
42	Mean escape depth of signal photoelectrons from amorphous and polycrystalline solids. Physical Review B, 1996, 54, 10927-10937.	1.1	64
43	Evaluation of electron inelastic mean free paths for selected elements and compounds. Surface and Interface Analysis, 2000, 29, 108-114.	0.8	62
44	Growth of giant magnetoresistance spin valves using Pb and Au as surfactants. Journal of Applied Physics, 1996, 80, 5183-5191.	1.1	61
45	Calculations of stopping powers of 100 eV to 30 keV electrons in 10 elemental solids. Surface and Interface Analysis, 2005, 37, 978-988.	0.8	60
46	The energy dependence of electron attenuation lengths. Surface and Interface Analysis, 1985, 7, 256-262.	0.8	59
47	Proliferation of Faulty Materials Data Analysis in the Literature. Microscopy and Microanalysis, 2020, 26, 1-2.	0.2	59
48	Energy calibration of x-ray photoelectron spectrometers: Results of an interlaboratory comparison to evaluate a proposed calibration procedure. Surface and Interface Analysis, 1995, 23, 121-132.	0.8	55
49	Elastic-electron-scattering effects on angular distributions in x-ray-photoelectron spectroscopy. Physical Review B, 1994, 50, 4739-4748.	1.1	54
50	Plasmon Damping in Metals. Physical Review, 1966, 145, 209-217.	2.7	52
51	Standard test data for estimating peak parameter errors in x-ray photoelectron spectroscopy III. Errors with different curve-fitting approaches. Surface and Interface Analysis, 2000, 29, 856-872.	0.8	52
52	Calculations of electron inelastic mean free paths from experimental optical data. Surface and Interface Analysis, 1985, 7, 263-274.	0.8	49
53	Evaluation of correction parameters for elastic-scattering effects in x-ray photoelectron spectroscopy and Auger electron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1997, 15, 2095-2106.	0.9	47
54	Excitation of Ï€ Electrons in Polystyrene and Similar Polymers by 20â€keV Electrons. Journal of Chemical Physics, 1963, 39, 630-634.	1.2	46

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55	Attenuation lengths of low-energy electrons in solids derived from the yield of proton-excited Auger electrons: beryllium and aluminum. Physical Review B, 1977, 16, 1370-1379.	1.1	45
56	Calculations of stopping powers of 100eVâ€“30keV electrons in 31 elemental solids. Journal of Applied Physics, 2008, 103, .	1.1	45
57	NIST databases with electron elastic-scattering cross sections, inelastic mean free paths, and effective attenuation lengths. Surface and Interface Analysis, 2005, 37, 1068-1071.	0.8	44
58	Effects of Contamination on the Characteristic Loss Spectrum of Tungsten. Physical Review, 1958, 110, 657-660.	2.7	43
59	Evaluating the Internal Structure of Coreâ€“Shell Nanoparticles Using X-ray Photoelectron Intensities and Simulated Spectra. Journal of Physical Chemistry C, 2015, 119, 17687-17696.	1.5	41
60	Monte Carlo strategies for simulations of electron backscattering from surfaces. Surface and Interface Analysis, 2005, 37, 861-874.	0.8	39
61	New universal expression for the electron stopping power for energies between 200 eV and 30 keV. Surface and Interface Analysis, 2006, 38, 76-83.	0.8	39
62	Innershell Ionization Cross Sections. , 1985, , 198-231.		39
63	Surface oxidation as a diffusion barrier for Al deposited on ferromagnetic metals. Journal of Applied Physics, 2001, 89, 5209-5214.	1.1	34
64	Influence of elastic-electron scattering on measurements of silicon dioxide film thicknesses by x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2001, 19, 2604-2611.	0.9	34
65	Excitation ofL-Shell Electrons in Al andAl2O3by 20-keV Electrons. Physical Review, 1968, 167, 592-600.	2.7	33
66	L3VVAuger-Electron Line Shapes and Peak Positions for Near-Threshold Electron Excitation in Nickel and Copper. Physical Review Letters, 1981, 46, 953-956.	2.9	33
67	Interpretation of nanoparticle X-ray photoelectron intensities. Applied Physics Letters, 2014, 104, .	1.5	33
68	Growth and trends in Auger-electron spectroscopy and x-ray photoelectron spectroscopy for surface analysis. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2003, 21, S42-S53.	0.9	31
69	Quantitative interpretation of molecular dynamics simulations for X-ray photoelectron spectroscopy of aqueous solutions. Journal of Chemical Physics, 2016, 144, 154704.	1.2	31
70	High-Resolution Measurements of theL3M2,3M4,5Auger Transitions in Nickel and Copper. Physical Review Letters, 1972, 29, 1153-1156.	2.9	30
71	Recent developments in quantitative surface analysis by electron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1986, 4, 1532-1539.	0.9	30
72	Improved algorithm for calculating transport cross sections of electrons with energies from<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:mrow><mml:mn>50</mml:mn><mml:mspace width="0.3em" /><mml:mi>eV</mml:mi><mml:mspace width="0.3em" /><mml:mtext>to</mml:mtext><mml:mspace width="0.3em" /><mml:mn>30</mml:mn><mml:mspace width="0.3em" /><mml:mi>keV</mml:mi></mml:mrow></mml:math>. Physical Review B, 2007, 76, .	1.1	30

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73	Effective Attenuation Lengths for Different Quantitative Applications of X-ray Photoelectron Spectroscopy. Journal of Physical and Chemical Reference Data, 2020, 49, .	1.9	30
74	Comparisons of calculated and measured effective attenuation lengths for silicon dioxide over a wide electron energy range. Surface Science, 2001, 488, L547-L552.	0.8	29
75	Development of the web-based NIST X-ray Photoelectron Spectroscopy (XPS) Database. Data Science Journal, 2002, 1, 1-12.	0.6	28
76	Comparisons of Analytical Approaches for Determining Shell Thicknesses of Coreâ€“Shell Nanoparticles by X-ray Photoelectron Spectroscopy. Journal of Physical Chemistry C, 2018, 122, 4073-4082.	1.5	28
77	The energy dependence of electron inelastic mean free paths. Surface and Interface Analysis, 1987, 10, 349-354.	0.8	27
78	Growth of Surface Analysis and the Development of Databases and Modeling Software for Auger-Electron Spectroscopy and X-ray Photoelectron Spectroscopy. Microscopy Today, 2016, 24, 16-23.	0.2	26
79	Thin Al, Au, Cu, Ni, Fe, and Ta films as oxidation barriers for Co in air. Journal of Applied Physics, 2003, 93, 8731-8733.	1.1	24
80	Modified predictive formula for the electron stopping power. Journal of Applied Physics, 2008, 103, .	1.1	24
81	The development of standards for surface analysis. Surface and Interface Analysis, 1988, 11, 103-109.	0.8	23
82	Standard test data for estimating peak-parameter errors in x-ray photoelectron spectroscopy. I. Peak binding energies. Surface and Interface Analysis, 1998, 26, 939-956.	0.8	23
83	Hot-electron attenuation lengths in ultrathin magnetic films. Journal of Applied Physics, 2000, 87, 5164-5166.	1.1	23
84	Differences in the Characteristic Electron Energy-Loss Spectra of Solid and Liquid Bismuth. Physical Review Letters, 1965, 15, 852-854.	2.9	22
85	Large Final-State Effects in the Core-Level Electron Energy-Loss Spectra of Vanadium at Low Incident-Electron Energies. Physical Review Letters, 1983, 51, 61-64.	2.9	22
86	Simulation of Electron Spectra for Surface Analysis (SESSA)for quantitative interpretation of (hard) X-ray photoelectron spectra(HAXPES). Journal of Electron Spectroscopy and Related Phenomena, 2013, 190, 137-143.	0.8	22
87	Effective attenuation lengths for quantitative determination of surface composition by Auger-electron spectroscopy and X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2017, 218, 1-12.	0.8	22
88	Inelastic Scattering of Kilovolt Electrons by Solids and Liquids. Health Physics, 1967, 13, 1265-1276.	0.3	21
89	High-Resolution Measurements of Auger-Electron and Photoelectron Structure in the Secondary-Electron Energy Distributions of Aluminum, Nickel, and Copper. Physical Review B, 1972, 6, 4418-4429.	1.1	21
90	Distinguishability of N composition profiles in SiON films on Si by angle-resolved x-ray photoelectron spectroscopy. Applied Physics Letters, 2006, 89, 172101.	1.5	21

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91	Evaluation of Two Methods for Determining Shell Thicknesses of Coreâ€“Shell Nanoparticles by X-ray Photoelectron Spectroscopy. Journal of Physical Chemistry C, 2016, 120, 22730-22738.	1.5	20
92	Calculations of electron inelastic mean free paths. XIII. Data for 14 organic compounds and water over the 50 eV to 200 keV range with the relativistic full Penn algorithm. Surface and Interface Analysis, 2022, 54, 534-560.	0.8	20
93	Consistency of calculated and measured electron inelastic mean free paths. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1999, 17, 1122-1126.	0.9	19
94	Effect of backscattered electrons on the analysis area in scanning Auger microscopy. Applied Surface Science, 2004, 230, 327-333.	3.1	19
95	Suppression of orange-peel coupling in magnetic tunnel junctions by preoxidation. Applied Physics Letters, 2006, 88, 162508.	1.5	19
96	Sample-morphology effects on x-ray photoelectron peak intensities. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2013, 31, .	0.9	18
97	Formal databases for surface analysis: The current situation and future trends. Surface and Interface Analysis, 1991, 17, 308-314.	0.8	17
98	Recommended Auger-electron kinetic energies for 42 elemental solids. Journal of Electron Spectroscopy and Related Phenomena, 2010, 182, 11-18.	0.8	17
99	Determination of the Beâ€“Augerâ€electron attenuation length in Be using 160â€keV protons. Applied Physics Letters, 1977, 30, 357-359.	1.5	16
100	Surface chemical analysisâ€"report on the vamas project. Surface and Interface Analysis, 1986, 9, 79-83.	0.8	16
101	Lowâ€temperature growth of giant magnetoresistance spin valves. Journal of Applied Physics, 1996, 79, 282-290.	1.1	16
102	Characterization of the imaging properties of a double-pass cylindrical-mirror analyzer. Surface and Interface Analysis, 1986, 9, 111-117.	0.8	15
103	The tradeâ€off between large magnetoresistance and small coercivity in symmetric spin valves. Journal of Applied Physics, 1996, 79, 8603-8606.	1.1	15
104	Evaluation of uncertainties in X-ray photoelectron spectroscopy intensities associated with different methods and procedures for background subtraction. I. Spectra for monochromatic Al X-ray. Surface and Interface Analysis, 2009, 41, 269-294.	0.8	15
105	elsepaâ€"Dirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules (New Version Announcement). Computer Physics Communications, 2021, 261, 107704.	3.0	15
106	Progress of the ASTM E-42 committee on surface analysis. Surface and Interface Analysis, 1981, 3, 94-98.	0.8	14
107	The status of reference data, reference materials and reference procedures in surface analysis. Surface and Interface Analysis, 1988, 13, 46-50.	0.8	14
108	Experimental determination of electron effective attenuation lengths in silicon dioxide thin films using synchrotron radiation I. Data analysis and comparisons. Surface and Interface Analysis, 2000, 29, 330-335.	0.8	14

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109	Refined calculations of effective attenuation lengths for SiO2 film thicknesses by x-ray photoelectron spectroscopy. Applied Physics Letters, 2006, 89, 252116.	1.5	14
110	Structure on the Highâ€Energy Side of the KL23M Auger Peak from Solid Aluminum: Internal Photoemission. Applied Physics Letters, 1972, 20, 335-337.	1.5	13
111	Standard test data for estimating peak parameter errors in x-ray photoelectron spectroscopy: II. Peak intensities. Surface and Interface Analysis, 2000, 29, 444-459.	0.8	13
112	Intermixing of aluminum-magnetic transition-metal bilayers. Journal of Applied Physics, 2003, 93, 8044-8046.	1.1	13
113	Improvements in the Reliability of X-ray Photoelectron Spectroscopy for Surface Analysis. Journal of Chemical Education, 2004, 81, 1734.	1.1	13
114	Effective attenuation lengths for photoelectrons in thin films of silicon oxynitride and hafnium oxynitride on silicon. Surface and Interface Analysis, 2013, 45, 628-638.	0.8	12
115	Imaging properties and energy aberrations of a doubleâ€pass cylindricalâ€mirror electron energy analyzer. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1986, 4, 1551-1556.	0.9	11
116	Development of standards for surface analysis by ISO technical committee 201 on surface chemical analysis. Surface and Interface Analysis, 1997, 25, 860-868.	0.8	11
117	Energy calibration of X-ray photoelectron spectrometers. Part III: Location of the zero point on the binding-energy scale. Surface and Interface Analysis, 1998, 26, 606-614.	0.8	11
118	Experimental determination of electron effective attenuation lengths in silicon dioxide thin films using synchrotron radiation II. Effects of elastic scattering. Surface and Interface Analysis, 2000, 29, 336-340.	0.8	11
119	Summary of ISO/TC 201 Standard: XXIX. ISO 20903: 2006â€"Surface chemical analysisâ€"Auger electron spectroscopy and X-ray photoelectron spectroscopyâ€"methods used to determine peak intensities and information required when reporting results. Surface and Interface Analysis, 2007, 39, 464-466.	0.8	11
120	Effects of elastic scattering and analyzerâ€acceptance angle on the analysis of angleâ€resolved Xâ€ray photoelectron spectroscopy data. Surface and Interface Analysis, 2011, 43, 1046-1056.	0.8	11
121	Sample-morphology effects on x-ray photoelectron peak intensities. II. Estimation of detection limits for thin-film materials. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2014, 32, .	0.9	11
122	Development of standards for reliable surface analyses by ISO technical committee 201 on surface chemical analysis. Surface and Interface Analysis, 2015, 47, 127-134.	0.8	11
123	Variation of the threshold energies for coreâ€electron excitation in electron energyâ€loss spectra as a function of incident electron energy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1983, 1, 1165-1168.	0.9	10
124	Dependence of calculated electron effective attenuation lengths on transport mean free paths obtained from two atomic potentials. Surface and Interface Analysis, 2006, 38, 1348-1356.	0.8	10
125	New Data Resources and Applications for AES and XPS. Journal of Surface Analysis (Online), 2014, 20, 155-160.	0.1	10
126	Energy transfers in the quasielastic scattering of 70â€"1250-eV electrons by surfaces. Physical Review B, 1989, 40, 7284-7287.	1.1	9

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127	Formation of Technical Committee 201 on Surface Chemical Analysis by the International Organization for Standardization. Surface and Interface Analysis, 1993, 20, 322-325.	0.8	9
128	Interface intermixing and in-plane grain size in aluminum transition-metal bilayers. Journal of Applied Physics, 2004, 96, 7278-7282.	1.1	9
129	Summary of ISO/TC 201 Technical Report: ISO/TR 19319: 2003â€"Surface chemical analysisâ€"Auger electron spectroscopy and x-ray photoelectron spectroscopyâ€"Determination of lateral resolution, analysis area and sample area viewed by the analyser. Surface and Interface Analysis, 2004, 36, 666-667.	0.8	9
130	Inelastic Mean Free Paths, Mean Escape Depths, Information Depths, and Effective Attenuation Lengths for Hard X-ray Photoelectron Spectroscopy. Springer Series in Surface Sciences, 2016, , 111-140.	0.3	9
131	Quantitative analysis of trace levels of surface contamination by Xâ€ray photoelectron spectroscopy. Part II: Systematic uncertainties and absolute quantification. Surface and Interface Analysis, 2017, 49, 1214-1224.	0.8	9
132	New correlation effects observed for inner-shell excitations in titanium and vanadium. Physical Review Letters, 1987, 58, 507-510.	2.9	8
133	Activities of ISO technical committee 201 on surface chemical analysis. Surface and Interface Analysis, 1994, 21, 615-620.	0.8	8
134	Use of the Bethe equation for inner-shell ionization by electron impact. Journal of Applied Physics, 2016, 119, .	1.1	8
135	X-ray photoemission spectroscopy of environmental particles. Environmental Science & Technology, 1984, 18, 58-61.	4.6	7
136	Simulation of parallel angle-resolved X-ray photoelectron spectroscopy data. Surface and Interface Analysis, 2010, 42, 1072-1075.	0.8	7
137	Quantitative analysis of trace levels of surface contamination by Xâ€ray photoelectron spectroscopy. Part I: Statistical uncertainty near the detection limit. Surface and Interface Analysis, 2017, 49, 1187-1205.	0.8	7
138	Validity of Inelastic-Electron-Scattering Data in Determining the Metallic or Insulating Properties of Adsorbed Atomic Layers. Physical Review B, 1970, 1, 4191-4192.	1.1	6
139	Simulated photoelectron intensities at the aqueous solutionâ€"air interface for flat and cylindrical (microjet) geometries. Physical Chemistry Chemical Physics, 2017, 19, 6330-6333.	1.3	6
140	Summary of ISO/TC 201 standards: introduction. Surface and Interface Analysis, 1999, 27, 691-692.	0.8	5
141	Effective attenuation length dependence on photoelectron kinetic energy for gold from 1 keV to 10 keV: Role of island growth in overlayer experiments. Journal of Electron Spectroscopy and Related Phenomena, 2019, 236, 27-32.	0.8	5
142	Summary Abstract: Comparison of L3â€shell excitation energies of 3d transition metals obtained by XPS, AEAPS, and EELS. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1984, 2, 840-841.	0.9	4
143	Evaluation of uncertainties in X-ray photoelectron spectroscopy intensities associated with different methods and procedures for background subtraction. II. Spectra for unmonochromated Al and Mg X-rays. Surface and Interface Analysis, 2009, 41, 804-813.	0.8	4
144	Practical formulas for inner-shell ionization cross sections by electron impact: Applications in quantitative Auger electron spectroscopy. Journal of Applied Physics, 2009, 106, 053706.	1.1	4

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145	Photoelectron angular distributions of Cu, Ag, Pt and Au samples: experiments and simulations. Surface and Interface Analysis, 2011, 43, 934-939.	0.8	4
146	Sample-morphology effects on x-ray photoelectron peak intensities. III. Simulated spectra of model coreâ€“shell nanoparticles. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2015, 33, .	0.9	4
147	Martin Seah: An extraordinary scientist and metrologist. Surface and Interface Analysis, 2022, 54, 285-293.	0.8	4
148	Applications of the National Institute of Standards and Technology (NIST) database for the simulation of electron spectra for surface analysis for quantitative x-ray photoelectron spectroscopy of nanostructures. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2021, 39, 063205.	0.9	4
149	Report on the 42nd IUVSTA workshop â€˜Electron scattering in solids: from fundamental concepts to practical applicationsâ€™. Surface and Interface Analysis, 2006, 38, 88-117.	0.8	3
150	Electron inelastic mean free paths in compounds. Journal of Surface Analysis (Online), 2019, 26, 106-107.	0.1	3
151	Semiautomated Dataâ€Recording and Control System for an Electron Energy Analyzer. Review of Scientific Instruments, 1973, 44, 1031-1033.	0.6	2
152	Surface analysis by electron spectroscopy at high pressures. Journal of Vacuum Science and Technology, 1978, 15, 549-552.	1.9	2
153	Measurement of silicon dioxide film thicknesses by X-ray photoelectron spectroscopy. AIP Conference Proceedings, 2001, , .	0.3	2
154	Dependence of electron inelastic mean free paths on electron energy and materials at low energy region. I: Elements.. Shinku/Journal of the Vacuum Society of Japan, 1990, 33, 58-62.	0.2	2
155	Origin of exchange decoupling effects in high-coercivity air-annealed CoPd multilayers. Journal of Applied Physics, 2005, 97, 10J104.	1.1	1
156	Interlaboratory study comparing analyses of simulated angleâ€resolved Xâ€ray photoelectron spectroscopy data. Surface and Interface Analysis, 2014, 46, 321-332.	0.8	1
157	Evaluation of electron inelastic mean free paths for selected elements and compoundsâ€. , 2000, 29, 108.		1
158	Electron Inelastic Mean Free Paths in Organic Materials Especially for Polyethylene and Guanine.. Hyomen Kagaku, 1994, 15, 175-180.	0.0	0
159	Summary of the panel discussion on opportunities and needs. Surface and Interface Analysis, 2005, 37, 1072-1074.	0.8	0